



UNIVERSITÀ  
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NATIONAL PHD SCHOOL IN  
MICRO AND NANO ELECTRONICS  
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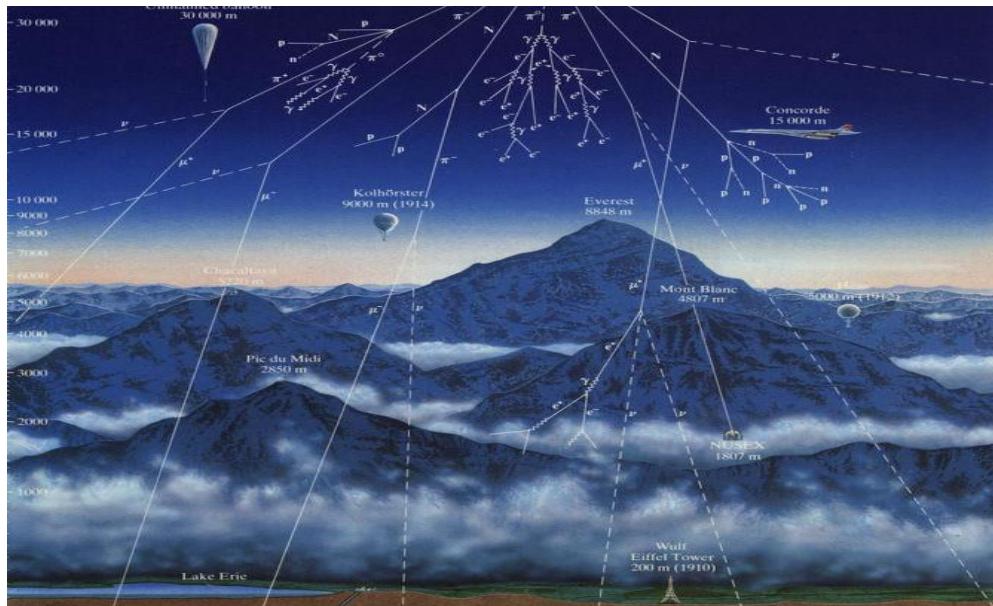
April 17th, 4PM  
Magenta Seminar Room  
Dept. ECBE, D Floor

# Radiation Hardening: background, definition and solutions in Smart Power Technologies

**Speaker: Andrea M. Veggetti (STMicroelectronics)**



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**Abstract:** Soft errors caused by wandering particles hitting electronic devices are a major reliability concern in all critical applications. On Earth, the major sources of ionizing radiation responsible for these effects are atmospheric neutrons, and alpha-emitting contaminants inside chip and package materials. In this presentation it will be presented the impact on semiconductor devices and the techniques used to mitigate/prevent their effects.